



Sheet 1 of 2

Form PTO-1449 Modified List of Patent and Publications Cited by Applicant (Use several sheets if necessary) U.S. Department of Commerce Patent and Trademark Office		Docket No. ABTT-0352/B020690	Application No. 10/644,371
		Applicant Ahmet Yigit, et al.	
		Filing Date August 20, 2003	Group Not Yet Assigned 2876
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
<i>jjt</i>	1	Dismukes, J.P., "Factory Level Metrics: Basis for Productivity Improvement", International Conference on Modeling and Analysis of Semiconductor Manufacturing (MASM), Tempe, Arizona 2002, 5 pages No month.	
EXAMINER <i>James J. Emerson</i>		DATE CONSIDERED <i>4/16/2005</i>	

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Not Yet Assigned**U. S. PATENT DOCUMENTS**

Examiner Initial		Document No.	Date	Name	Class	Subclass
<i>gzo</i>	2	2001/0027418 A1	10/04/01	Johnson	705	22
<i>gzo</i>	3	2001/0032025	10/18/01	Lenz, et al.	700	28

FOREIGN PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Country	Translation	
					YES	NO

EXAMINER *James J. Timmerman*DATE CONSIDERED *4/16/2005*